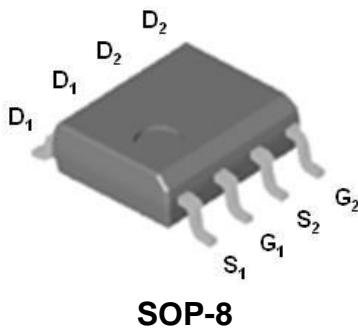


P1504HV

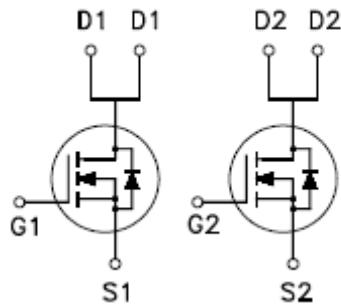
Dual N-Channel Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
40V	23mΩ @ $V_{GS} = 10V$	7A



100% UIS tested
100% Rg tested



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	40	V
Gate-Source Voltage	V_{GS}	± 25	
Continuous Drain Current $T_A = 25^\circ C$	I_D	7	A
$T_A = 100^\circ C$	I_D	4	
Pulsed Drain Current ¹	I_{DM}	30	
Avalanche Current	I_{AS}	28	
Avalanche Energy	E_{AS}	41	mJ
Power Dissipation $T_A = 25^\circ C$	P_D	2	W
$T_A = 100^\circ C$	P_D	0.8	
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Lead	$R_{\theta JL}$		25	°C / W
Junction-to-Ambient	$R_{\theta JA}$		62.5	

¹Pulse width limited by maximum junction temperature.

P1504HV

Dual N-Channel Enhancement Mode MOSFET

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

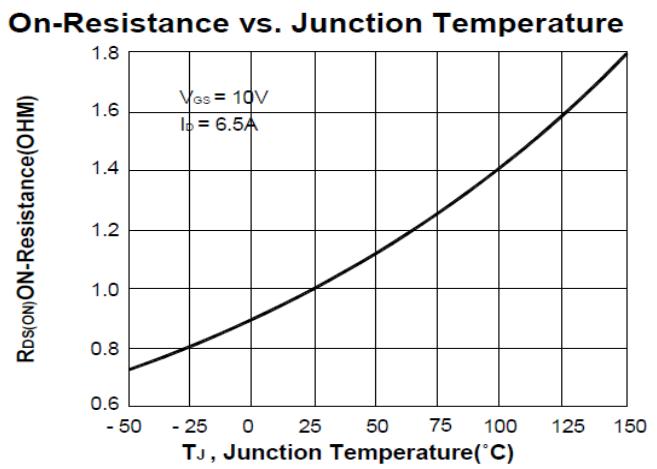
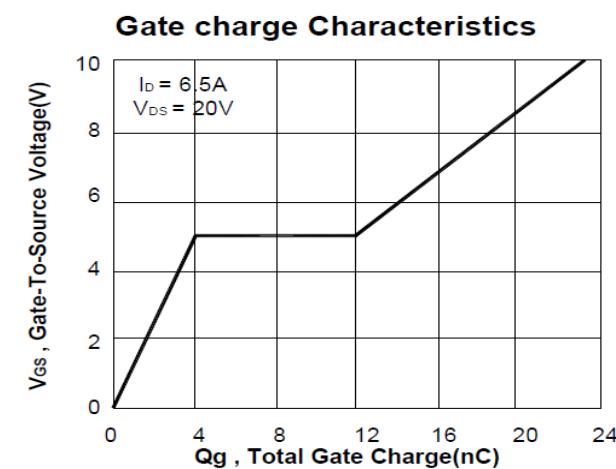
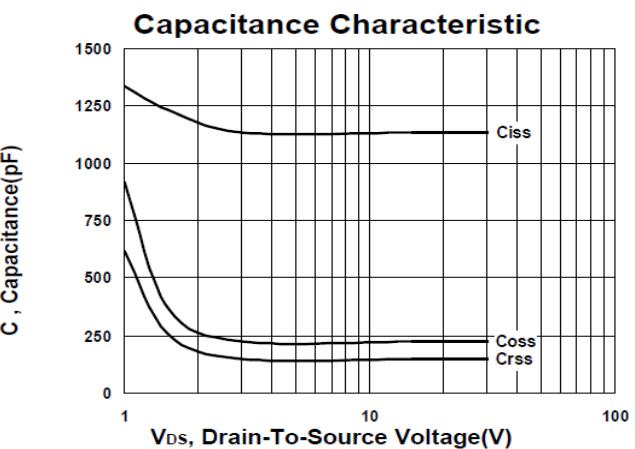
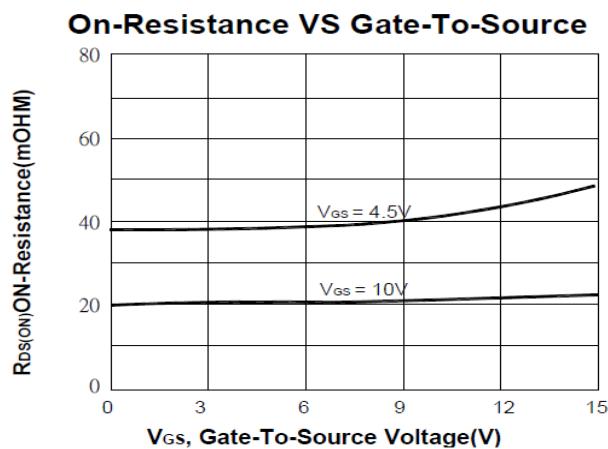
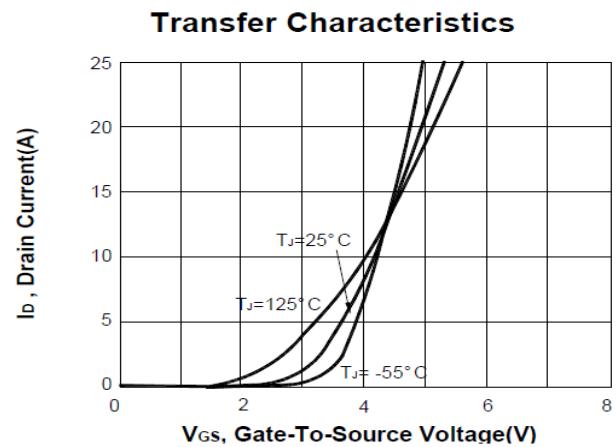
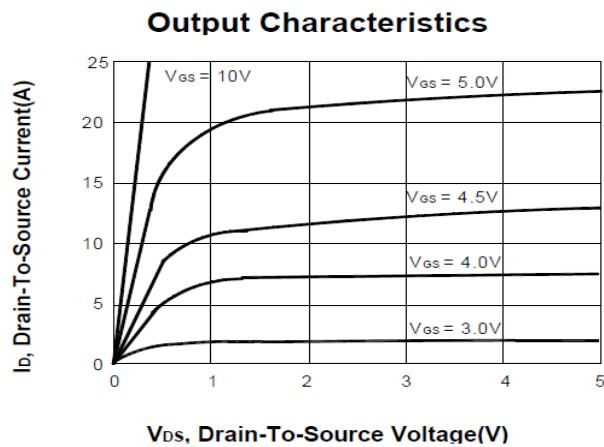
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	40			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.5	2.3	3.0	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 25\text{V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 32\text{V}, V_{\text{GS}} = 0\text{V}$			1	μA
		$V_{\text{DS}} = 30\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 70^\circ\text{C}$			10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 5\text{V}, V_{\text{GS}} = 10\text{V}$	30			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 7\text{V}, I_D = 6.5\text{A}$		22	28	$\text{m}\Omega$
		$V_{\text{GS}} = 10\text{V}, I_D = 6.5\text{A}$		20	23	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = 5\text{V}, I_D = 6.5\text{A}$		30		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 20\text{V}, f = 1\text{MHz}$		1132		pF
Output Capacitance	C_{oss}			222		
Reverse Transfer Capacitance	C_{rss}			146		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.6		Ω
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, V_{\text{GS}} = 10\text{V}, I_D = 6.5\text{A}$		23		nC
Gate-Source Charge ²	Q_{gs}			8		
Gate-Drain Charge ²	Q_{gd}			4		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, I_D \approx 6.5\text{A}, V_{\text{GS}} = 10\text{V}, R_G = 6\Omega$		10		nS
Rise Time ²	t_r			20		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			35		
Fall Time ²	t_f			52		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Continuous Current	I_S				7	A
Forward Voltage ¹	V_{SD}	$I_F = 6.5\text{A}, V_{\text{GS}} = 0\text{V}$			1.3	V
Reverse Recovery Time	t_{rr}	$I_F = 6.5\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		25		nS
Reverse Recovery Charge	Q_{rr}			18		nC

¹Pulse test : Pulse Width $\leq 300\text{ }\mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

P1504HV

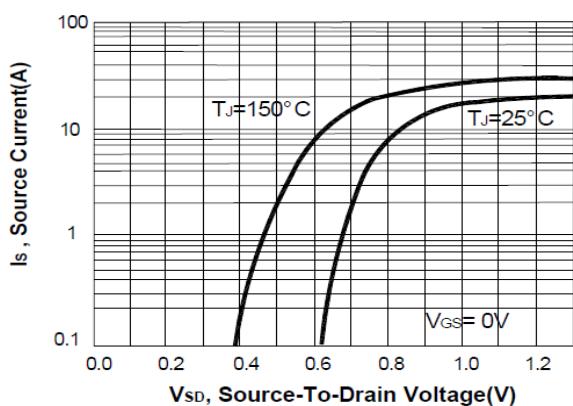
Dual N-Channel Enhancement Mode MOSFET



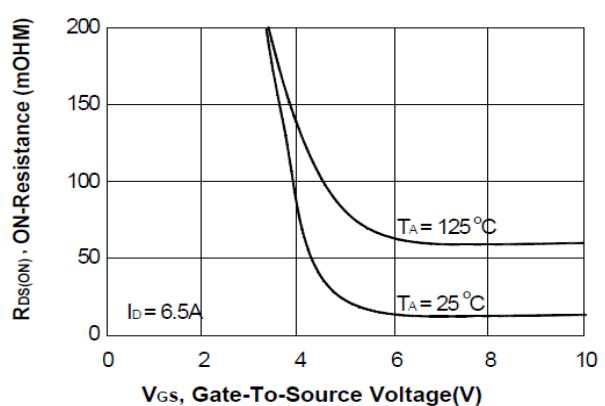
P1504HV

Dual N-Channel Enhancement Mode MOSFET

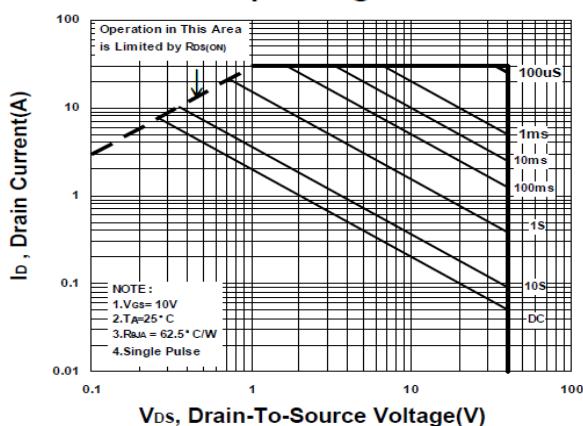
Body Diode Forward Voltage VS Source current



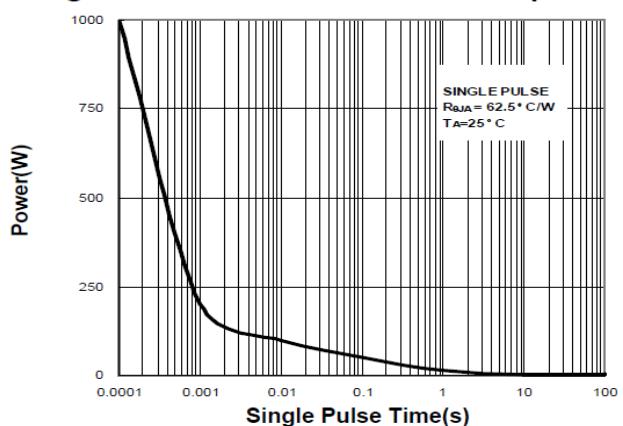
On-Resistance VS Gate-To-Source



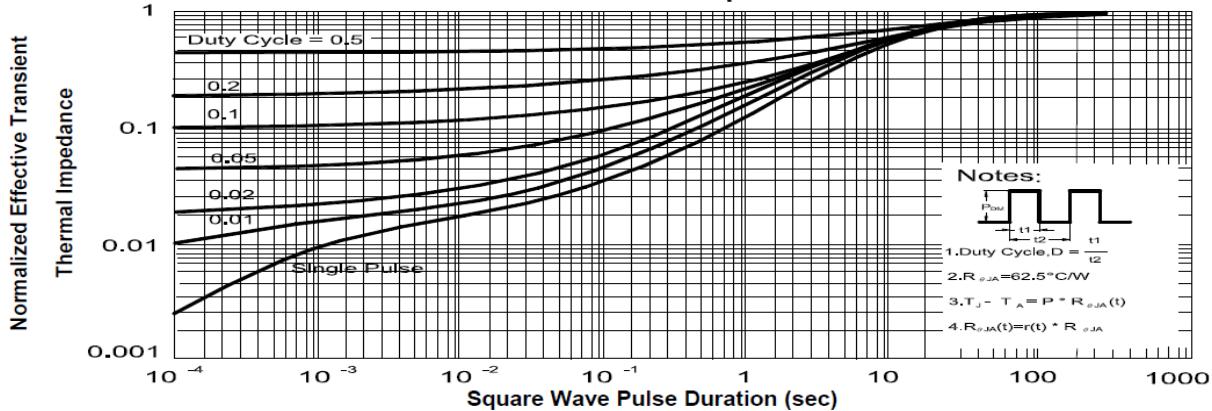
Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curve



P1504HV

Dual N-Channel Enhancement Mode MOSFET

Package Dimension

SOP-8 MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	4.8	4.9	5.0	H	0.4	0.6	0.93
B	3.8	3.9	4.0	I	0.19	0.21	0.25
C	5.79	6.0	6.2	J	0.25	0.375	0.5
D	0.33	0.4	0.51	K	0°	3°	18°
E	1.25	1.27	1.29				
F	1.1	1.3	1.65				
G	0.05	0.15	0.25				

